


<b>Search Notes</b>  	<b>Application/Control No.</b>  10598529	<b>Applicant(s)/Patent Under Reexamination</b>  HAMANAKA, MASAHIKO
	<b>Examiner</b>  STEPHEN R KOZIOL	<b>Art Unit</b>  2624

### SEARCHED

Class	Subclass	Date	Examiner
382	106, 118	3/23/2011	srk

### SEARCH NOTES

Search Notes	Date	Examiner
PALM inventor name double patenting search	3/23/2011	srk
EAST text search of above-cited classes for object pose estimation using weighted sharpness differences	3/23/2011	srk
NPL IEEE search for object pose estimation using weighted sharpness differences	3/23/2011	srk
JPO patent and utility model gazette db abstract search for object pose estimation using weighted sharpness differences	3/23/2011	srk

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
382	106	3/23/2011	srk
	EAST PGPub interference text search of above-cited class. See EAST interference search report.	3/23/2011	srk

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